

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-07
CB Certificate No.: 50600097 ITL

Schedule Number: IECQ-L ULTW 16.0003-07-S Rev No.: 6 Revision Date: 2023/08/15 Page 1 of 1

Appendix-1 (50600097 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Scanning Electron Microscope (SEM)	T-SEM-3
Transmission Electron Microscope - Electron Energy Loss Spectroscopy (TEM-EELS)	T-TEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
Emission Microscopy (EMMI)-InGaAs	T-EFA-3
Optical Microscope (OM)	T-OMI-3
IC Layout Imaging	T-OMI-3
Decapsulation-Chemical, Laser	T-LAB-3
Delayer	T-LAB-3
Thermal Emission Microscope (THEMOS)	T-EFA-3

Technical Reviewer of DQS: Michael Chou Da	ate:	8/15/2023
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